
**Optics and photonics — General
optical test methods — Measurement
of relative irradiance in the image field**

*Optique et photonique — Méthodes générales d'essai optique —
Méthode de mesure de l'éclairement énergétique relatif dans le
champ image*

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Foreword

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This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 1, *Fundamental standards*.

This second edition cancels and replaces the first edition (ISO 13653:1996), which has been technically revised.

The main changes compared to the previous edition are as follows:

- A second option for measurement, which does not require a rotation of the specimen but allows to measure along an image diameter, has been included in 7.2.3.

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